

<b>Notice of References Cited</b>	Application/Control No. 10/529,732	Applicant(s)/Patent Under Reexamination DE VAAN, ADRIANUS JOHANNE	
	Examiner William C. Dowling	Art Unit 2851	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
*	B	US-2007/0076175	04-2007	Nakagawa et al.	353/085
*	C	US-2006/0139578	06-2006	Nakagawa et al.	353/085
	D	US-			
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	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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